

CDx4HC374 三态正边沿触发式高速 CMOS 逻辑八路 D 型触发器

1 特性

- 缓冲输入
- 通用三态输出使能控制
- 三态输出
- 总线驱动能力
- 当 $V_{CC} = 5V$, $C_L = 15pF$, $T_A = 25^\circ C$ 时的传播延迟典型值 (时钟到 Q) = 15ns
- 扇出 (在温度范围内)
 - 标准输出: 10 个 LSTTL 负载
 - 总线驱动器输出: 15 个 LSTTL 负载
- 宽工作温度范围: $-55^\circ C$ 至 $125^\circ C$
- 平衡的传播延迟及转换时间
- 与 LSTTL 逻辑 IC 相比, 可显著降低功耗
- HC 类型
 - 2V 至 6V 工作电压
 - 高抗噪性: 当 $V_{CC} = 5V$ 时, $N_{IL} = 30\%$, $N_{IH} = V_{CC}$ 的 30%
- HCT 类型
 - 4.5V 至 5.5V 工作电压
 - 直接 LSTTL 输入逻辑兼容性, $V_{IL} = 0.8V$ (最大值), $V_{IH} = 2V$ (最小值)
 - CMOS 输入兼容性, 当电压为 V_{OL} 、 V_{OH} 时, $I_I \leq 1\mu A$

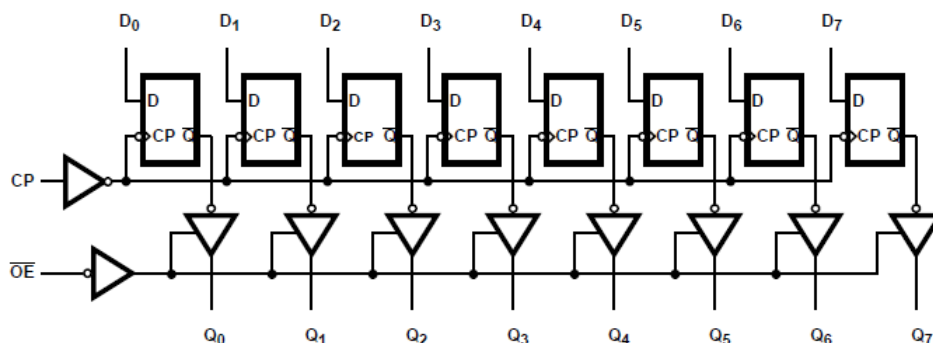
2 说明

' HC374、' HCT374、' HC574 和 ' HCT574 是八路 D 型触发器, 具有三态输出, 能够驱动 15 个 LSTTL 负载。八个边沿触发式触发器在时钟 (CP) 从低电平向高电平转换时将数据输入其寄存器。输出使能端 (OE) 控制三态输出, 不受寄存器操作的影响。当 OE 为高电平时, 输出处于高阻态。374 和 574 功能相同, 只是引脚排列方式不同。

器件信息

器件型号	封装 ⁽¹⁾	封装尺寸 (标称值)
CD54HC374F3A	CDIP (20)	26.92mm × 6.92mm
CD54HC574F	CDIP (20)	26.92mm × 6.92mm
CD54HCT374F3A	CDIP (20)	26.92mm × 6.92mm
CD54HCT574F	CDIP (20)	26.92mm × 6.92mm
CD74HC374M	SOIC (20)	12.80mm × 7.50mm
CD74HC574M	SOIC (20)	12.80mm × 7.50mm
CD74HCT374M	SOIC (20)	12.80mm × 7.50mm
CD74HCT574M	SOIC (20)	12.80mm × 7.50mm
CD74HC374E	PDIP (20)	25.40mm × 6.35mm
CD74HC574E	PDIP (20)	25.40mm × 6.35mm
CD74HCT374E	PDIP (20)	25.40mm × 6.35mm
CD74HCT574E	PDIP (20)	25.40mm × 6.35mm
CD74HCT574PWR	TSSOP (20)	6.50mm × 4.40mm

(1) 如需了解所有可用封装, 请参阅数据表末尾的可订购产品附录。



功能图



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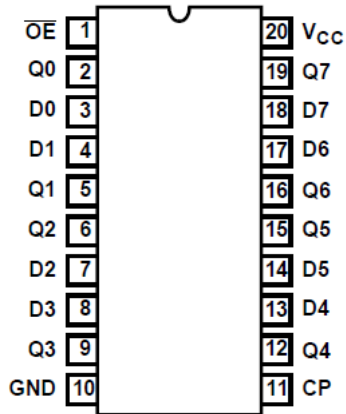
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3 Revision History

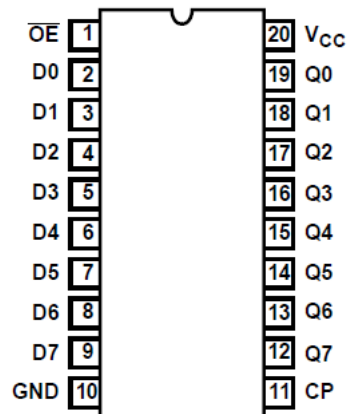
注：以前版本的页码可能与当前版本的页码不同

Changes from Revision C (May 2004) to Revision D (January 2022)	Page
• 更新了整个文档中的编号、格式、表格、图和交叉参考，以反映现代数据表标准.....	1

4 Pin Configuration and Functions



HC(T) 374
 J, DW, or N package
 20-Pin CDIP, SOIC, or PDIP
 Top View



HC(T) 574
 J, DW, N, or PW package
 20-Pin CDIP, SOIC, PDIP, or TSSOP
 Top View

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage	- 0.5	7	V
I _{IK}	Input diode current	For V _I < - 0.5 V or V _I > V _{CC} + 0.5 V		±20 mA
I _{OK}	Output diode current	For V _O < - 0.5 V or V _O > V _{CC} + 0.5 V		±20 mA
I _O	Drain current, per output	For - 0.5 V < V _O < V _{CC} + 0.5 V		±35 mA
I _O	Output source or sink current per output pin	For V _O > - 0.5 V or V _O < V _{CC} + 0.5 V		±25 mA
Continuous current through V _{CC} or ground current				±50 mA
T _J	Junction temperature			150 °C
T _{stg}	Storage temperature range	- 65	150	°C
Lead temperature (Soldering 10s) (SOIC - Lead Tips Only)				300 °C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions

		MIN	MAX	UNIT	
V _{CC}	Supply voltage range	HC types	2	6	V
		HCT types	4.5	5.5	
V _I , V _O	DC input or output voltage	0	V _{CC}	V	
	Input rise and fall time	2 V		1000	ns
		4.5 V		500	
		6 V		400	
T _A	Temperature range	- 55	125	°C	

5.3 Thermal Information

THERMAL METRIC		DW (SOIC)	N (PDIP)	PW (TSSOP)	UNIT
		20 PINS	20 PINS	20 PINS	
R _{θJA}	Junction-to-ambient thermal resistance ⁽¹⁾	58	69	83	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC package thermal metrics](#) application report.

5.4 Electrical Characteristics

PARAMETER		TEST CONDITIONS ⁽²⁾	V _{CC} (V)	25°C			- 40°C to 85°C		- 55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
V _{IH}	High level input voltage		2	1.5			1.5		1.5		V
			4.5	3.15			3.15		3.15		
			6	4.2			4.2		4.2		
V _{IL}	Low level input voltage		2	0.5			0.5		0.5		V
			4.5	1.35			1.35		1.35		
			6	1.8			1.8		1.8		
V _{OH}	High level output voltage CMOS loads	I _{OH} = - 20 μA	2	1.9			1.9		1.9		V
		I _{OH} = - 20 μA	4.5	4.4			4.4		4.4		
		I _{OH} = - 20 μA	6	5.9			5.9		5.9		
	High level output voltage TTL loads	I _{OH} = - 6 mA	4.5	3.98			3.84		3.7		V
I _{OH} = - 7.8 mA		6	5.48			5.34		5.2			
V _{OL}	Low level output voltage CMOS loads	I _{OL} = 20 μA	2	0.1			0.1		0.1		V
		I _{OL} = 20 μA	4.5	0.1			0.1		0.1		
		I _{OL} = 20 μA	6	0.1			0.1		0.1		
	Low level output voltage TTL loads	I _{OL} = 6 mA	4.5	0.26			0.33		0.4		V
		I _{OL} = 7.8 mA	6	0.26			0.33		0.4		
I _I	Input leakage current	V _I = V _{CC} or GND	6	±0.1			±1		±1		μA
I _{CC}	Quiescent device current	V _I = V _{CC} or GND	6	8			80		160		μA
V _{IL} or V _{IH}	Three-state leakage current	V _O = V _{CC} or GND	6	±0.5			±5.0		±10		μA
HCT TYPES											
V _{IH}	High level input voltage		4.5 to 5.5	2			2		2		V
V _{IL}	Low level input voltage		4.5 to 5.5	0.8			0.8		0.8		V
V _{OH}	High level output voltage CMOS loads	I _{OH} = - 20 μA	4.5	4.4			4.4		4.4		V
	High level output voltage TTL loads	I _{OH} = - 6 mA	4.5	3.98			3.84		3.7		
V _{OL}	Low level output voltage CMOS loads	I _{OL} = 20 μA	4.5	0.1			0.1		0.1		V
	Low level output voltage TTL loads	I _{OL} = 6 mA	4.5	0.26			0.33		0.4		
I _I	Input leakage current	V _I = V _{CC} or GND	5.5	±0.1			±1		±1		μA
I _{CC}	Quiescent device current	V _I = V _{CC} or GND	5.5	8			80		160		μA
V _{IL} or V _{IH}	Three-state leakage current	V _O = V _{CC} or GND	6	±0.5			±5.0		±10		μA

5.4 Electrical Characteristics (continued)

PARAMETER		TEST CONDITIONS ⁽²⁾	V _{CC} (V)	25°C			- 40°C to 85°C		- 55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Δ I _{CC} ⁽¹⁾	HCT374 Additional quiescent device current per input pin	D0 - D7 inputs held at V _{CC} - 2.1	4.5 to 5.5		100	108		135		147	μ A
		CP input held at V _{CC} - 2.1	4.5 to 5.5		100	324		405		441	μ A
		\overline{OE} input held at V _{CC} - 2.1	4.5 to 5.5		100	468		585		637	μ A
	HCT574 Additional quiescent device current per input pin	D0 - D7 inputs held at V _{CC} - 2.1	4.5 to 5.5		100	144		180		196	μ A
		CP input held at V _{CC} - 2.1	4.5 to 5.5		100	270		337.5		367.5	μ A
		\overline{OE} input held at V _{CC} - 2.1	4.5 to 5.5		100	216		270		294	μ A

(1) For dual-supply systems, theoretical worst case (V_I = 2.4 V, V_{CC} = 5.5 V) specification is 1.8mA.

(2) V_I = V_{IH} or V_{IL}, unless otherwise noted.

5.5 Prerequisite for Switching Characteristics

PARAMETER		V _{CC} (V)	25°C			- 40°C to 85°C			- 55°C to 125°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
HC TYPES												
f _{MAX}	Maximum clock frequency	2	6		5		4				MHz	
		4.5	30		25		20					
		6	35		29		23					
t _W	Clock pulse width	2	80		100		120				ns	
		4.5	16		20		24					
		6	14		17		20					
t _{SU}	Setup time data to clock	2	60		75		90				ns	
		4.5	12		15		18					
		6	10		13		15					
t _H	Hold time data to clock	2	5		5		5				ns	
		4.5	5		5		5					
		6	5		5		5					
HCT TYPES												
f _{MAX}	Maximum clock frequency	4.5	30		25		20				MHz	
t _W	Clock pulse width	4.5	16		20		24				ns	
t _{SU}	Setup time data to clock	4.5	12		15		18				ns	
t _H	Hold time data to clock	4.5	5		5		5				ns	

5.6 Switching Characteristics

 $C_L = 50 \text{ pF}$, Input t_r , $t_f = 6 \text{ ns}$

PARAMETER		TEST CONDITIONS	V_{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
t_{PLH} , t_{PHL}	Propagation delay Clock to output	$C_L = 50 \text{ pF}$	2		165		205		250	ns	
			4.5		33		41		50		
	Clock to output	$C_L = 15 \text{ pF}$	5		15					ns	
		$C_L = 50 \text{ pF}$	6		28		35		43		
t_{PLZ} , t_{PHZ}	Output disable to Q	$C_L = 50 \text{ pF}$	2		135		170		205	ns	
			4.5		27		34		41		
	Output disable to Q	$C_L = 15 \text{ pF}$	5		11					ns	
		$C_L = 50 \text{ pF}$	6		23		29		35		
t_{PZL} , t_{PZH}	Output enable to Q	$C_L = 50 \text{ pF}$	2		150		190		225	ns	
			4.5		30		38		45		
	Output enable to Q	$C_L = 15 \text{ pF}$	5		12					ns	
		$C_L = 50 \text{ pF}$	6		26		33		38		
f_{MAX}	Maximum clock frequency	$C_L = 15 \text{ pF}$	5		60					MHz	
t_{THL} , t_{TLH}	Output transition time	$C_L = 50 \text{ pF}$	2		60		75		90	ns	
			4.5		12		15		18		
			6		10		13		15		
C_I	Input capacitance	$C_L = 50 \text{ pF}$		10	10		10	10		pF	
C_O	Three-state output capacitance			20	20		20	20		pF	
C_{PD}	Power dissipation capacitance ^{(1) (2)}	$C_L = 15 \text{ pF}$	5		39					pF	
HCT TYPES											
t_{PHL} , t_{PLH}	Propagation delay Clock to output	$C_L = 50 \text{ pF}$	4.5		33		41		50	ns	
		$C_L = 15 \text{ pF}$	5		15						
t_{PLZ} , t_{PHZ}	Output disable to Q	$C_L = 50 \text{ pF}$	4.5		28		35		42	ns	
		$C_L = 15 \text{ pF}$	5		11						
t_{PZL} , t_{PZH}	Output enable to Q	$C_L = 50 \text{ pF}$	4.5		30		38		45	ns	
		$C_L = 15 \text{ pF}$	5		12						
f_{MAX}	Maximum clock frequency	$C_L = 15 \text{ pF}$	5		60					MHz	
t_{TLH} , t_{THL}	Output transition time	$C_L = 50 \text{ pF}$	4.5		12		15		18	ns	
C_I	Input capacitance	$C_L = 50 \text{ pF}$		10	10		10	10		pF	
C_O	Three-state output capacitance			20	20		20	20		pF	
C_{PD}	Power dissipation capacitance ^{(1) (2)}	$C_L = 15 \text{ pF}$	5		47					pF	

(1) C_{PD} is used to determine the dynamic power consumption, per package.

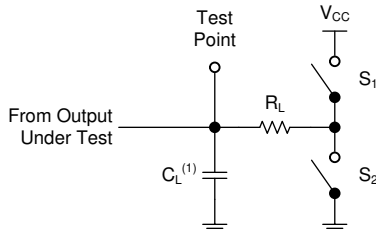
(2) $P_D = C_{PD} V_{CC}^2 f_i + \sum V_{CC}^2 f_o C_L$ where f_i = input frequency, f_o = output frequency, C_L = output load capacitance, V_{CC} = supply voltage.

6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O = 50 \Omega$, $t_f < 6 \text{ ns}$.

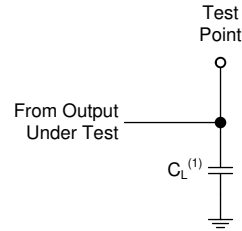
For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



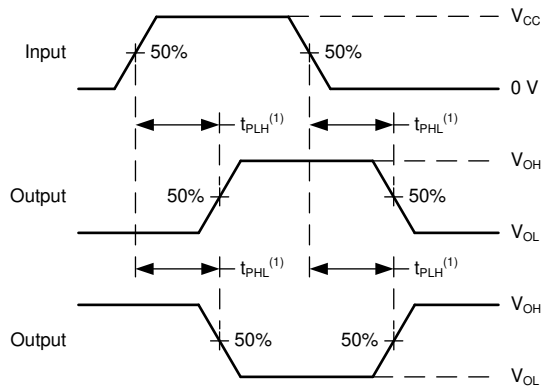
(1) C_L includes probe and test-fixture capacitance.

图 6-1. Load Circuit for 3-State Outputs



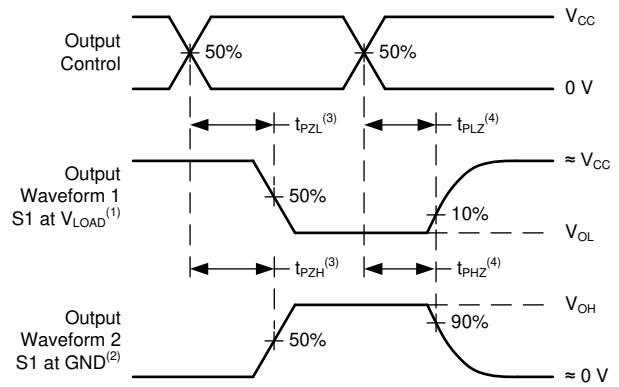
(1) C_L includes probe and test-fixture capacitance.

图 6-2. Load Circuit for Push-Pull Outputs



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

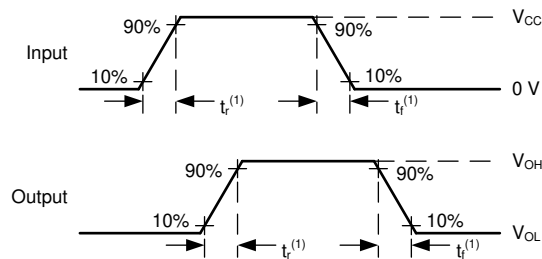
图 6-3. Voltage Waveforms, Propagation Delays for Standard CMOS Inputs



(1) t_{PZL} and t_{PHZ} are the same as t_{dis} .

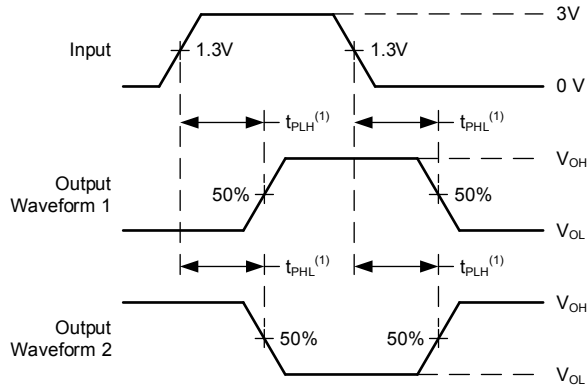
(2) t_{PZL} and t_{PHZ} are the same as t_{en} .

图 6-4. Voltage Waveforms, Standard CMOS Inputs Propagation Delays



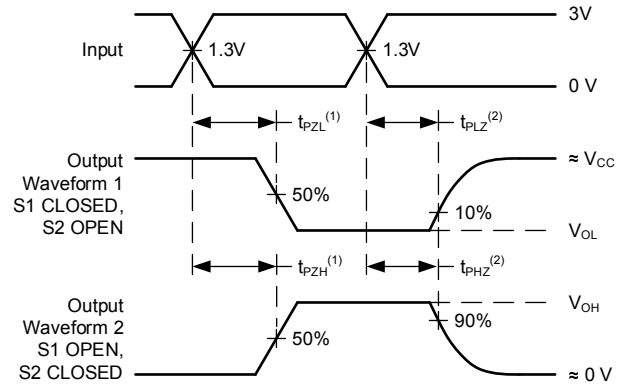
(1) The greater between t_r and t_f is the same as t_t .

图 6-5. Voltage Waveforms, Input and Output Transition Times for Standard CMOS Inputs



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

图 6-6. Voltage Waveforms, Propagation Delays for TTL-Compatible Inputs



(1) t_{PLZ} and t_{PHZ} are the same as t_{dis} .

(2) t_{PZL} and t_{PZH} are the same as t_{en} .

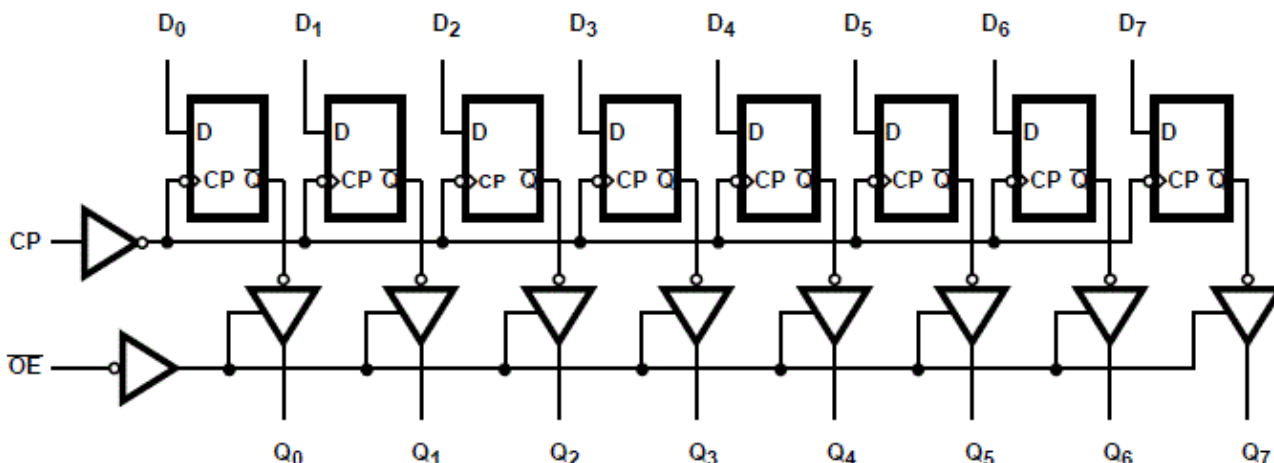
图 6-7. Voltage Waveforms, TTL-Compatible CMOS Inputs Propagation Delays

7 Detailed Description

7.1 Overview

The ' HC374, ' HCT374, ' HC574, and ' HCT574 are octal D-type flip-flops with 3-state outputs and the capability to drive 15 LSTTL loads. The eight edge-triggered flip-flops enter data into their registers on the LOW to HIGH transition of clock (CP). The output enable (\overline{OE}) controls the 3-state outputs and is independent of the register operation. When \overline{OE} is HIGH, the outputs are in the high-impedance state. The 374 and 574 are identical in function and differ only in their pinout arrangements.

7.2 Functional Block Diagram



7.3 Device Functional Modes

表 7-1. Truth Table⁽¹⁾

INPUTS			OUTPUT
\overline{OE}	CP	Dn	Qn
L	↑	H	H
L	↑	L	L
L	L	X	Q0
H	X	X	Z

- (1) H = high level (steady state), L = low level (steady state), X = don't care, ↑ = transition from low to high level, Q0 = the level of Q before the indicated steady-state input conditions were established, Z = high impedance state

8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 接收文档更新通知

要接收文档更新通知，请导航至 ti.com 上的器件产品文件夹。点击 [订阅更新](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

10.2 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料，可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的《使用条款》。

10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-8974201RA	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8974201RA CD54HCT574F3A	Samples
CD54HC374F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8407101RA CD54HC374F3A	Samples
CD54HC574F	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HC574F	Samples
CD54HC574F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HC574F3A	Samples
CD54HCT374F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8550701RA CD54HCT374F3A	Samples
CD54HCT574F	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HCT574F	Samples
CD54HCT574F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8974201RA CD54HCT574F3A	Samples
CD74HC374E	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC374E	Samples
CD74HC374M	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC374M	Samples
CD74HC374M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC374M	Samples
CD74HC374M96E4	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC374M	Samples
CD74HC574E	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC574E	Samples
CD74HC574M	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC574M	Samples
CD74HC574M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC574M	Samples
CD74HC574M96E4	ACTIVE	SOIC	DW	20	2000	TBD	Call TI	Call TI	-55 to 125		Samples
CD74HC574M96G4	ACTIVE	SOIC	DW	20	2000	TBD	Call TI	Call TI	-55 to 125		Samples
CD74HCT374E	ACTIVE	PDIP	N	20	20	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT374E	Samples
CD74HCT374EE4	ACTIVE	PDIP	N	20	20	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT374E	Samples

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD74HCT374M	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT374M	Samples
CD74HCT374M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT374M	Samples
CD74HCT574E	ACTIVE	PDIP	N	20	20	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT574E	Samples
CD74HCT574M	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT574M	Samples
CD74HCT574M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT574M	Samples
CD74HCT574M96G4	ACTIVE	SOIC	DW	20	2000	TBD	Call TI	Call TI	-55 to 125		Samples
CD74HCT574ME4	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT574M	Samples
CD74HCT574PWR	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HK574	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD54HC374, CD54HC574, CD54HCT374, CD54HCT574, CD74HC374, CD74HC574, CD74HCT374, CD74HCT574 :

- Catalog : [CD74HC374](#), [CD74HC574](#), [CD74HCT374](#), [CD74HCT574](#)
- Automotive : [CD74HCT574-Q1](#), [CD74HCT574-Q1](#)
- Enhanced Product : [CD74HCT574-EP](#), [CD74HCT574-EP](#)
- Military : [CD54HC374](#), [CD54HC574](#), [CD54HCT374](#), [CD54HCT574](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Enhanced Product - Supports Defense, Aerospace and Medical Applications
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC374M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74HC574M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74HCT374M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74HCT574M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74HCT574PWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC374M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74HC574M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74HCT374M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74HCT574M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74HCT574PWR	TSSOP	PW	20	2000	356.0	356.0	35.0

TUBE


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CD74HC374E	N	PDIP	20	20	506	13.97	11230	4.32
CD74HC374M	DW	SOIC	20	25	507	12.83	5080	6.6
CD74HC574E	N	PDIP	20	20	506	13.97	11230	4.32
CD74HC574M	DW	SOIC	20	25	507	12.83	5080	6.6
CD74HCT374E	N	PDIP	20	20	506	13.97	11230	4.32
CD74HCT374EE4	N	PDIP	20	20	506	13.97	11230	4.32
CD74HCT374M	DW	SOIC	20	25	507	12.83	5080	6.6
CD74HCT574E	N	PDIP	20	20	506	13.97	11230	4.32
CD74HCT574M	DW	SOIC	20	25	507	12.83	5080	6.6
CD74HCT574ME4	DW	SOIC	20	25	507	12.83	5080	6.6

J (R-GDIP-T**)

14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



DIM \ PINS **	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



4040083/F 03/03

- NOTES:
- All linear dimensions are in inches (millimeters).
 - This drawing is subject to change without notice.
 - This package is hermetically sealed with a ceramic lid using glass frit.
 - Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
 - Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
 - The 20 pin end lead shoulder width is a vendor option, either half or full width.

DW0020A



PACKAGE OUTLINE

SOIC - 2.65 mm max height

SOIC



4220724/A 05/2016

NOTES:

- All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
- This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- Reference JEDEC registration MS-013.

EXAMPLE BOARD LAYOUT

DW0020A

SOIC - 2.65 mm max height

SOIC



LAND PATTERN EXAMPLE
SCALE:6X



SOLDER MASK DETAILS

4220724/A 05/2016

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DW0020A

SOIC - 2.65 mm max height

SOIC



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:6X

4220724/A 05/2016

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

PW0020A



PACKAGE OUTLINE

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



4220206/A 02/2017

NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
- This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- Reference JEDEC registration MO-153.

EXAMPLE BOARD LAYOUT

PW0020A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X



SOLDER MASK DETAILS

4220206/A 02/2017

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

PW0020A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220206/A 02/2017

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Publication IPC-7351 is recommended for alternate design.
 - D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 - E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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